

IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Previously Presented) A method of inspecting an array substrate comprising a plurality of gate and signal lines disposed on the substrate and intersecting perpendicularly with each other, a switching element disposed on each intersecting portion of the gate lines and the signal lines, a pixel capacitance electrically connected to each switching element, a plurality of connection pads into which signals are inputted, and a selection circuit having at least a switch that distributes signals inputted from each of said connection pads to at least one signal line of a signal line group including a plurality of signal lines sequentially,

the method of inspecting an array substrate comprising the steps of:

writing signals into a first signal line in a first signal line selection period in which said switch selects said first signal line from the signal line group;

reading signals from a second signal line in a second signal line selection period following said first signal line selection period in which said switch selects said second signal line from said signal line group; and

inspecting a short circuit between said first signal line and said second signal line based upon the read signals.

2. (Previously Presented) The method of inspecting an array substrate according to claim 1, wherein said first signal line and said second signal line are selected by a first switch that is part of the selection circuit, and signals are written and read via a first connection pad connected to the first switch.

3. (Previously Presented) The method of inspecting an array substrate according to claim 1, wherein said first signal line and said second signal line are selected by the first switch and the second switch respectively, which are both part of the selection circuit and

signals are written and read via a first connection pad and a second connection pad connected respectively to the first switch and the second switch.

4. (Cancelled)

5. (Cancelled)

6. (Currently Amended) The method of inspecting an array substrate according to claim 1, wherein said signals input into said plurality of connecting pads are inputted from an external drive circuit that converts inputted digital signals into analog signals, and divides said signal lines into a plurality of signal line groups composed of a predetermined number of signal lines and outputs analog signals corresponding to each of said signal line groups serially, and wherein

said selection circuit distributes serial analog signals from said drive circuit to a corresponding signal line of each of said signal line group sequentially.

7. (Original) The method of inspecting an array substrate according to claim 6, wherein said drive circuit is mounted on a flexible wiring substrate and is connected electrically to said array substrate.

8. (Original) The method of inspecting an array substrate according to claim 1, wherein said array substrate includes integrally a gate line drive means supplying drive signals to said gate line.

9-16. (Cancelled)